

<b>Notice of References Cited</b>	Application/Control No. 10/023,235		Applicant(s)/Patent Under Reexamination BERNSTEIN ET AL.	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	K	US-			
	L	US-			
	M	US-			

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